

<b>Notice of References Cited</b>	Application/Control No. 10/085,587	Applicant(s)/Patent Under Reexamination EBIHARA, HITOSHI	
	Examiner Po-Wei (Dennis) Chen	Art Unit 2676	Page 1 of 1

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	C	US-			
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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